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**Frequency-dependent Full Counting Statistics of Electron Transport in Double Quantum Dots** RAMON AGUADO, DAVID MARCOS, CSIC, CLIVE EMARY, TOBIAS BRANDES, Technische Universität Berlin — Full Counting Statistics is a powerful tool to study correlations in stochastic processes. It has been applied in the last years to characterize nanoscale transport. We present a technique that allows to calculate finite frequency high-order correlators of the electronic current through an interacting nanostructure. We illustrate our technique by calculating the frequency-dependent shot noise (second order) and skewness (third order) of a double quantum dot. Our results demonstrate that the frequency-dependent skewness contains useful information about the internal quantum dynamics of the nanostructure in bias voltage regimes where the second-order correlations are dominated by thermal fluctuations.

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